



Patent
Attorney's Docket No. 014823-116

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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In re Patent Application of)

Shawn Smith, et al.)

Group Art Unit: 2784

Application No.: 09/192,164)

Examiner: Greene, J.

Filed: November 13, 1998)

For: IC TEST SOFTWARE SYSTEM)
FOR MAPPING LOGICAL)
FUNCTIONAL TEST DATA OF)
LOGIC INTEGRATED CIRCUITS)
TO PHYSICAL REPRESENTATION)

I hereby certify that the enclosed is a true and correct copy of the original as submitted to the United States Patent and Trademark Office, Washington, D.C. June 5, 2000.
MARIA REGINA CATIUS
Regulator
6-5-2000

RESPONSE UNDER 37 CFR §1.111

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

Responsive to the Office Action of February 3, 2000, please amend this application as follows:

IN THE CLAIMS:

1. (Amended) A method of automated defect localization in the testing of semiconductor integrated circuits, comprising the steps of:
- testing the integrated circuits to obtain generalized failure data;
 - inputting the generalized failure data and circuit models describing logical operations of the integrated circuits to a circuit analysis tool;
 - obtaining from the circuit analysis first localized probable defect data;
 - performing in-line inspection of the integrated circuits to obtain second localized probable defect data; and
 - correlating the first and second localized probable defect data.

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